

Notice of References Cited	Application/Control No. 09/890,758	Applicant(s)/Patent Under Reexamination ONISHI ET AL.	
	Examiner Heather D Gibbs	Art Unit 2622	Page 1 of 1

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	B	US-6,195,183	02-2001	Fujimoto et al.	358/514
	C	US-			
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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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